

Technical specifications:
Nanotec Scanning Probe Microscope
SPM Scanners



Long Scanner and Short Scanner

Nanotec[®] patented AFM and MFM piezoelectric scanners with concentric tubular design minimizing the thermal drift. Three screws allow to easily change from one scanner to a different one. It is recommended to purchase a long scanner for big surfaces or heights and a short one for the best resolution measurements.

AFM Long Scanner
Overall dimensions: 19.1 mm (0.75 inch) diameter and 100 mm (3.94 inch) length
Maximum horizontal range: 70 μm X 70 μm (typical)
Maximum vertical range: 12 μm (typical)
Magnet for the best fixing
X,Y,Z calibration parameters included
Optional: MFM long scanner removing the magnet
AFM Short Scanner
Overall dimensions: 19.1 mm (0.75 inch) diameter and 65 mm (2.56 inch) length
Maximum horizontal range: 10 μm X 10 μm (typical)
Maximum vertical range: 2 μm (typical)
RMS noise in the X,Y direction combined with the Dulcinea electronics < 0.67 \AA
RMS noise in the Z direction combined with the Dulcinea electronics < 0.13 \AA
Magnet for the best fixing
X,Y,Z calibration parameters included
Optional: MFM short scanner removing the magnet